

S-5471 Series

ENERGY HARVESTING VOLTAGE MONITORING IC WITH ULTRA-LOW CURRENT CONSUMPTION

www.ablicinc.com

© ABLIC Inc., 2017

Rev.1.1_01

The S-5471 Series, developed by using CMOS technology, is a voltage monitoring IC with an ultra-low current consumption.

Since the feed-through current in the IC is extremely low, the error can be reduced when the voltage of a power supply with high impedance is detected. In addition, since the detection voltage is extremely low, a tiny amount of power generated by energy harvesting can also be detected.

Due to its ultra-low current consumption and low-voltage operation, the S-5471 Series is suitable for battery-operated small mobile devices.

Features

- Ultra-low current consumption:
- Detection voltage:
- Wide operation voltage range:
- Operation temperature range:
- Lead-free (Sn 100%), halogen-free

Applications

· Miniaturization and power consumption reduction for various sensors of portable and wireless devices

 $I_{DD} \leq 10$ nA typ.

 $V_{DET} = 0.75 V \text{ typ.}$

 $V_{DD} = 0.7 V \text{ to } 5.5 V$ Ta = -40°C to +85°C

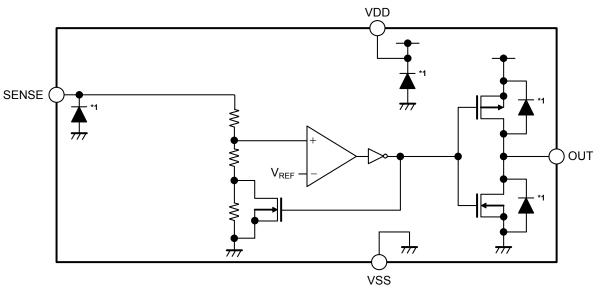
• Energy harvesting

Package

• SOT-23-5

ENERGY HARVESTING VOLTAGE MONITORING IC WITH ULTRA-LOW CURRENT CONSUMPTION S-5471 Series Rev.1.1_01

Block Diagram



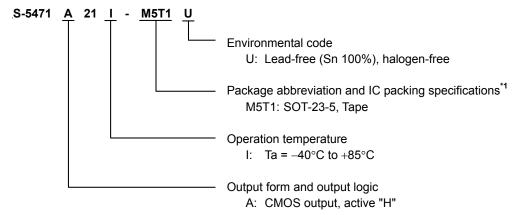
*1. Parasitic diode

Figure 1

Product Name Structure

Refer to **"1. Product name**" regarding the contents of the product name, **"2. Package**" regarding the package drawings.

1. Product name



*1. Refer to the tape drawing.

2. Package

 Table 1
 Package Drawing Codes

Package Name	Dimension	Таре	Reel
SOT-23-5	MP005-A-P-SD	MP005-A-C-SD	MP005-A-R-SD

Pin Configuration

1. SOT-23-5

Top view



Pin No.	Symbol	Description
1	VDD	Power supply pin
2	VSS	GND pin
3	TEST ^{*1}	Test pin
4	SENSE	Detection voltage input pin
5	OUT	Output pin

Table 2

Figure 2

*1. Connect to GND.

ABLIC Inc.

Absolute Maximum Ratings

Table 3

		(Ta = +25°C unless otherv	vise specified)
Item	Symbol	Absolute Maximum Rating	Unit
Power supply voltage	V _{DD}	$V_{\rm SS}-0.3$ to $V_{\rm SS}+7.0$	V
Input voltage	V _{SENSE}	$V_{\rm SS}-0.3$ to $V_{\rm SS}+7.0$	V
Output voltage	V _{OUT}	$V_{\text{SS}} - 0.3$ to $V_{\text{DD}} + 0.3$	V
Output ain ourreat	ISOURCE	20	mA
Output pin current	I _{SINK}	20	mA
Operation ambient temperature	T _{opr}	-40 to +85	°C
Storage temperature	T _{stg}	-55 to +125	С°

Caution The absolute maximum ratings are rated values exceeding which the product could suffer physical damage. These values must therefore not be exceeded under any conditions.

Thermal Resistance Value

Symbol Mi<u>n</u>. Unit Item Condition Typ. Max. Board A °C/W _ 192 _ Board B 160 °C/W _ _ Junction-to-ambient thermal resistance*1 SOT-23-5 Board C °C/W θ_{JA} _ Board D °C/W _ _ _ Board E °C/W _ _ _

Table 4

*1. Test environment: compliance with JEDEC STANDARD JESD51-2A

Remark Refer to "**■ Power Dissipation**" and "**Test Board**" for details.

ABLIC Inc.

ENERGY HARVESTING VOLTAGE MONITORING IC WITH ULTRA-LOW CURRENT CONSUMPTION S-5471 Series Rev.1.1_01

Electrical Characteristics

Table 5

			(Ta = +25	°C, V _{DD} :	= 3.0 V u	inless oth	nerwise s	pecified)
Item	Symbol	Condition		Min.	Тур.	Max.	Unit	Test Circuit
Power supply voltage	V _{DD}	Ta = -40°C to +85°C	C	0.7	-	5.5	V	-
		V _{SENSE} = V _{SS}		-	1	150	nA	1
Current consumption	I _{DD}	V _{SENSE} = 1.0 V		-	3	150	nA	1
Detection voltage	V _{DET}	_		0.69	0.75	0.81	V	2
Release voltage	V _{REL}	_		V _{DET} - 0.07	V _{DET} - 0.05	V _{DET} - 0.03	V	2
Detection voltage temperature coefficient	V _{TC}	Ta = -40°C to +85°C		_	-0.24	_	%/°C	_
Input current	I _{SENSE}	V _{SENSE} = 1.0 V		-	1.45	100	nA	3
Source ourrent	ISOURCE	V_{OUT} = $V_{DD} - 0.3 V$	V _{DD} = 0.7 V	0.01	0.3		mA	4
Source current			V _{DD} = 3.0 V	4.0	5.3	I	mA	4
Sink current	I _{SINK}	V - 0.2 V	V _{DD} = 0.7 V	0.01	0.6		mA	5
		V _{OUT} = 0.3 V	V _{DD} = 3.0 V	8.0	10.2		mA	5
Output response time	t _{OD}	_		-	-	15	ms	-

Test Circuits

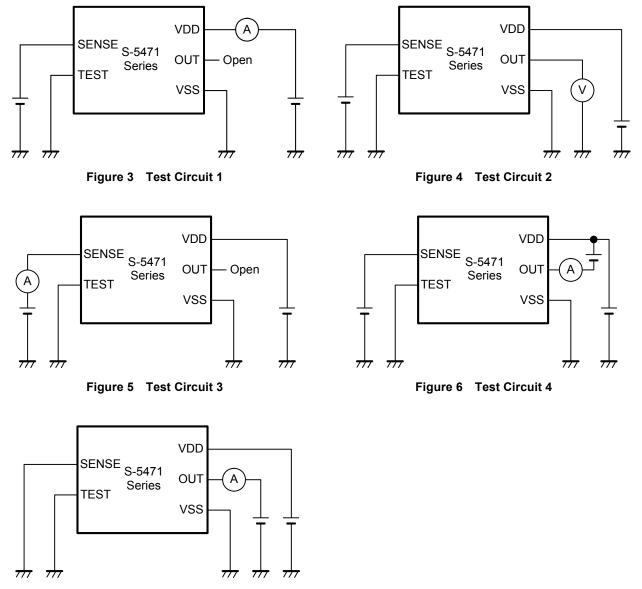
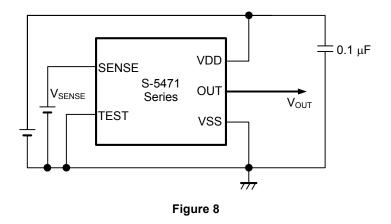


Figure 7 Test Circuit 5

Standard Circuit

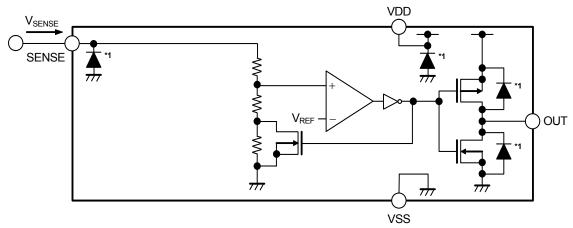


Caution The above connection diagram and constant will not guarantee successful operation. Perform thorough evaluation using the actual application to set the constant.

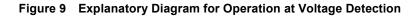
Operation

1. Basic operation

Figure 9 shows an explanatory diagram for the operation at voltage detection.



*1. Parasitic diode



- (1) If V_{SENSE} is lower than V_{DET} , "L" is output from the OUT pin.
- (2) If V_{SENSE} increases and becomes equal to or higher than V_{DET}, "H" is output from the OUT pin (point A in Figure 10). Even if V_{SENSE} decreases and falls below V_{DET}, as long as V_{SENSE} is higher than V_{REL}, "H" is output from the OUT pin.
- (3) If V_{SENSE} then decreases further and becomes equal to or lower than V_{REL}, "L" is output from the OUT pin (point B in Figure 10).
- Remark V_{SENSE}: Voltage input to the SENSE pin
 - Detection voltage (refer to "3. 1 Detection voltage (V_{DET})") V_{DET}:
 - V_{REL}:



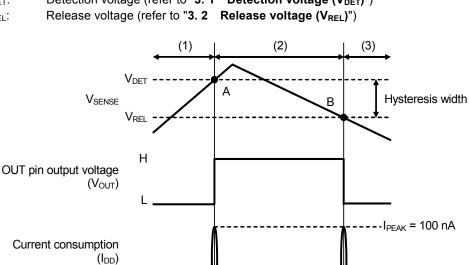
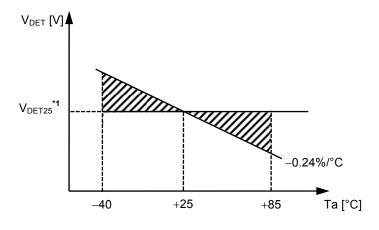


Figure 10 Operation at Voltage Detection

Caution Feed-through current (IPEAK = 100 nA) flows around the time when the OUT pin voltage switches, as shown in Figure 10. Therefore, if the VSENSE is fixed around this time, the current consumption will increase.

2. Temperature characteristics of detection voltage

The shaded area in **Figure 11** shows the temperature characteristics of the detection voltage in the operation temperature range.



*1. V_{DET25} : Detection voltage value at Ta = +25°C

Figure 11 Temperature Characteristics of Detection Voltage

3. Explanation of terms

3.1 Detection voltage (VDET)

The detection voltage (V_{DET}) is a voltage at which the output voltage (V_{OUT}) turns to "H".

The detection voltage varies slightly even among products with the same specification. The variation in detection voltage from the minimum detection voltage (V_{DET} min.) to the maximum detection voltage (V_{DET} max.) is called the detection voltage range (refer to **Figure 12**).

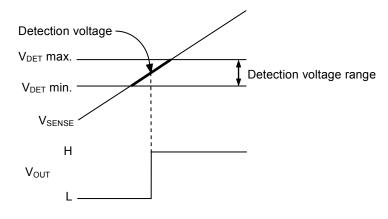


Figure 12 Detection Voltage

3. 2 Release voltage (V_{REL})

The release voltage (V_{REL}) is a voltage at which the output voltage (V_{OUT}) turns to "L".

The release voltage varies slightly even among products with the same specification. The variation in release voltage from the minimum release voltage (V_{REL} min.) to the maximum release voltage (V_{REL} max.) is called the release voltage range (refer to **Figure 13**).

The range is calculated from the actual detection voltage (V_{DET}) of a product and is in the range of $V_{DET} - 0.07 \le V_{REL} \le V_{DET} - 0.03$.

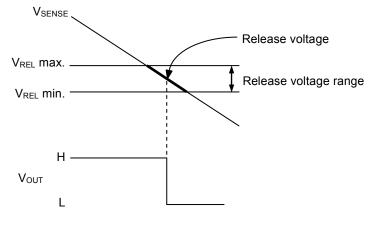


Figure 13 Release Voltage

3.3 Hysteresis width

The hysteresis width is the voltage difference between the detection voltage and the release voltage (voltage at point A – voltage at point B in "Figure 10 Operation at Voltage Detection").

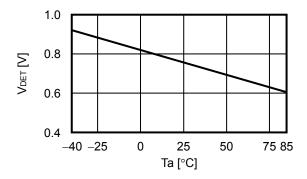
The hysteresis width between the detection voltage and the release voltage prevents malfunction caused by noise in the input voltage.

Precautions

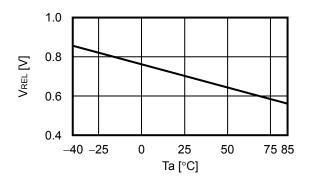
- Use the S-5471 Series with the output pin current of 20 mA or less.
- The S-5471 Series may malfunction if the power supply voltage changes steeply.
- The output in the S-5471 Series is unstable in lower voltage than the minimum operation voltage. At the time of power-on, use the S-5471 Series after output stabilization.
- Connect a capacitor of 0.1 μF or more between the VDD pin and VSS pin for stabilization.
- Since the SENSE pin is easy to be affected by disturbance noise, perform countermeasures such as mounting external parts to the IC as close as possible.
- If the impedance of the power supply is high, the S-5471 Series may malfunction due to voltage drop caused by feed-through current. Make wire patterns very carefully so that the impedance of the power supply lowers.
- Do not apply an electrostatic discharge to this IC that exceeds the performance ratings of the built-in electrostatic protection circuit.
- ABLIC Inc. claims no responsibility for any disputes arising out of or in connection with any infringement by products including this IC of patents owned by a third party.

Characteristics (Typical Data)

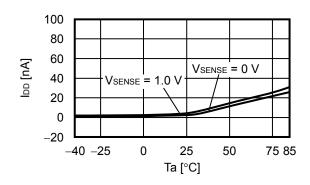
1. Detection voltage vs. Temperature



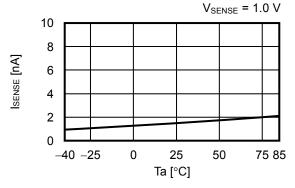
3. Release voltage vs. Temperature



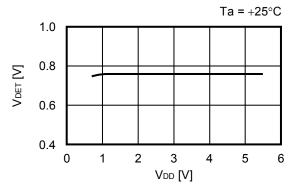
5. Current consumption vs. Temperature



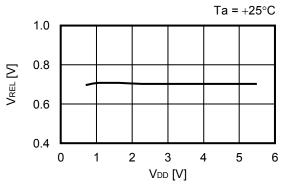
7. Input current vs. Temperature



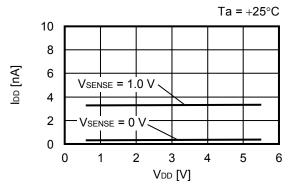
2. Detection voltage vs. Power supply voltage



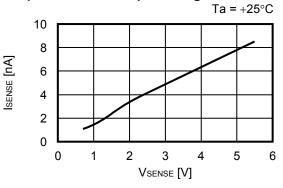
4. Release voltage vs. Power supply voltage

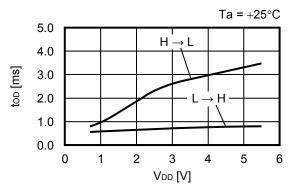


6. Current consumption vs. Power supply voltage



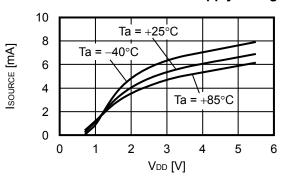
8. Input current vs. Input voltage



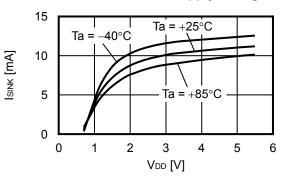


9. Output response time vs. Power supply voltage

10. Source current vs. Power supply voltage

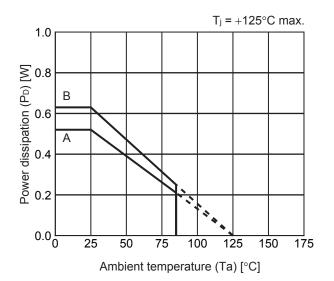


11. Sink current vs. Power supply voltage



Power Dissipation

SOT-23-5



Board	Power Dissipation (P _D)
А	0.52 W
В	0.63 W
С	_
D	_
E	_

SOT-23-3/3S/5/6 Test Board

) IC Mount Area

(1) Board A



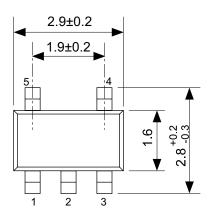
Item		Specification	
Size [mm]		114.3 x 76.2 x t1.6	
Material		FR-4	
Number of copper foil layer		2	
	1	Land pattern and wiring for testing: t0.070	
Copper foil layer [mm]	2	-	
Copper foil layer [mm]	3	-	
	4	74.2 x 74.2 x t0.070	
Thermal via		-	

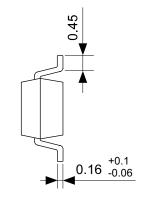
(2) Board B

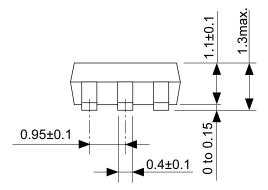


Item		Specification
Size [mm]		114.3 x 76.2 x t1.6
Material		FR-4
Number of copper foil layer		4
Copper foil layer [mm]	1	Land pattern and wiring for testing: t0.070
	2	74.2 x 74.2 x t0.035
	3	74.2 x 74.2 x t0.035
	4	74.2 x 74.2 x t0.070
Thermal via		-

No. SOT23x-A-Board-SD-2.0

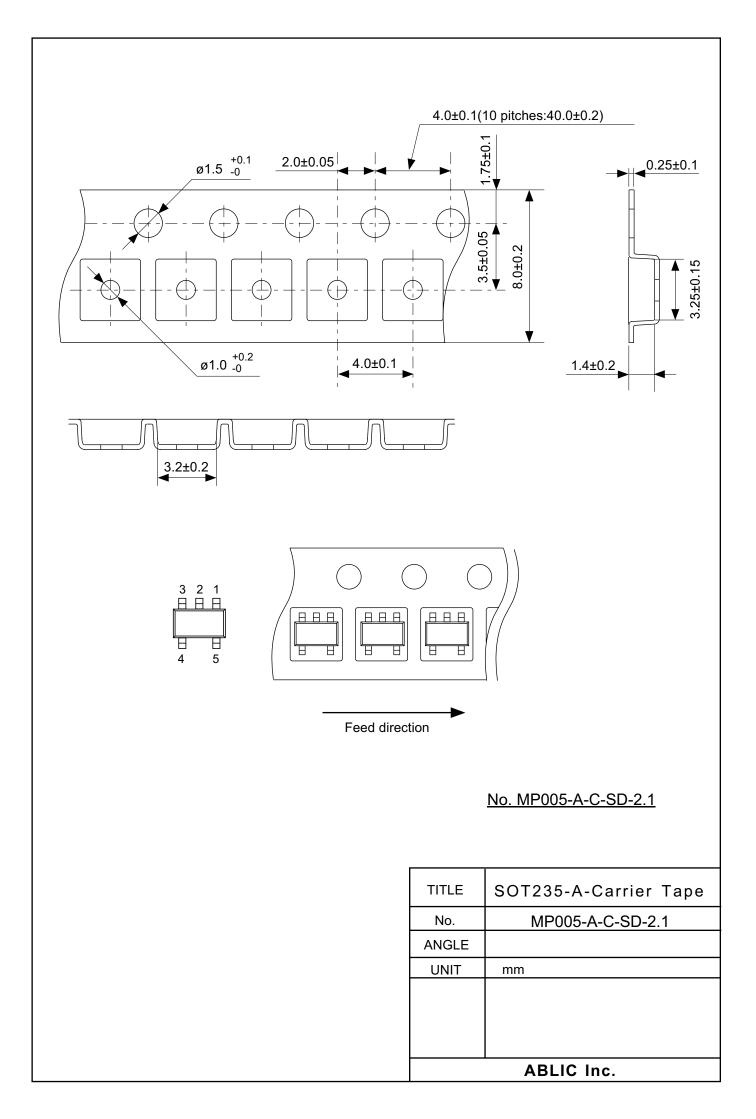


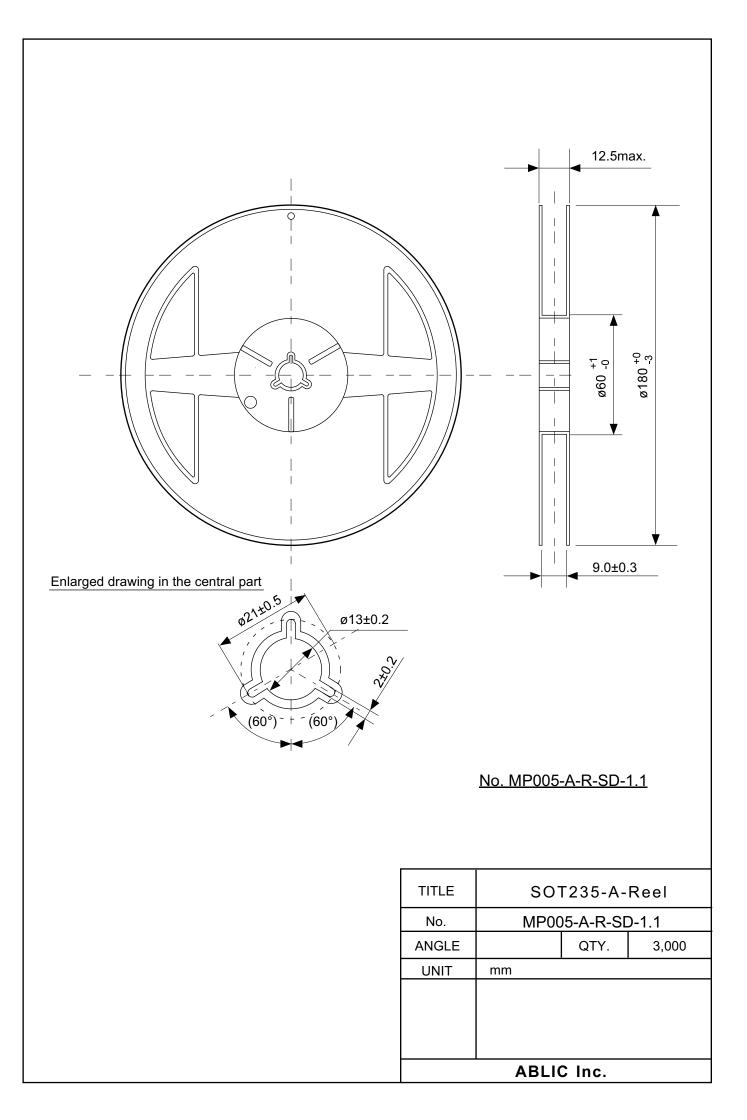




No. MP005-A-P-SD-1.3

TITLE	SOT235-A-PKG Dimensions		
No.	MP005-A-P-SD-1.3		
ANGLE			
UNIT	mm		
ABLIC Inc.			





Disclaimers (Handling Precautions)

- 1. All the information described herein (product data, specifications, figures, tables, programs, algorithms and application circuit examples, etc.) is current as of publishing date of this document and is subject to change without notice.
- The circuit examples and the usages described herein are for reference only, and do not guarantee the success of any specific mass-production design.
 ABLIC Inc. is not responsible for damages caused by the reasons other than the products described herein

ABLIC Inc. is not responsible for damages caused by the reasons other than the products described herein (hereinafter "the products") or infringement of third-party intellectual property right and any other right due to the use of the information described herein.

- 3. ABLIC Inc. is not responsible for damages caused by the incorrect information described herein.
- Be careful to use the products within their specified ranges. Pay special attention to the absolute maximum ratings, operation voltage range and electrical characteristics, etc.
 ABLIC Inc. is not responsible for damages caused by failures and / or accidents, etc. that occur due to the use of the products outside their specified ranges.
- 5. When using the products, confirm their applications, and the laws and regulations of the region or country where they are used and verify suitability, safety and other factors for the intended use.
- 6. When exporting the products, comply with the Foreign Exchange and Foreign Trade Act and all other export-related laws, and follow the required procedures.
- 7. The products must not be used or provided (exported) for the purposes of the development of weapons of mass destruction or military use. ABLIC Inc. is not responsible for any provision (export) to those whose purpose is to develop, manufacture, use or store nuclear, biological or chemical weapons, missiles, or other military use.
- 8. The products are not designed to be used as part of any device or equipment that may affect the human body, human life, or assets (such as medical equipment, disaster prevention systems, security systems, combustion control systems, infrastructure control systems, vehicle equipment, traffic systems, in-vehicle equipment, aviation equipment, aerospace equipment, and nuclear-related equipment), excluding when specified for in-vehicle use or other uses. Do not apply the products to the above listed devices and equipments without prior written permission by ABLIC Inc. Especially, the products cannot be used for life support devices, devices implanted in the human body and devices that directly affect human life, etc.

Prior consultation with our sales office is required when considering the above uses.

ABLIC Inc. is not responsible for damages caused by unauthorized or unspecified use of our products.

9. Semiconductor products may fail or malfunction with some probability. The user of the products should therefore take responsibility to give thorough consideration to safety design including redundancy, fire spread prevention measures, and malfunction prevention to prevent accidents causing injury or death, fires and social damage, etc. that may ensue from the products' failure or malfunction. The entire system must be sufficiently evaluated and applied on customer's own responsibility.

- 10. The products are not designed to be radiation-proof. The necessary radiation measures should be taken in the product design by the customer depending on the intended use.
- 11. The products do not affect human health under normal use. However, they contain chemical substances and heavy metals and should therefore not be put in the mouth. The fracture surfaces of wafers and chips may be sharp. Be careful when handling these with the bare hands to prevent injuries, etc.
- 12. When disposing of the products, comply with the laws and ordinances of the country or region where they are used.
- 13. The information described herein contains copyright information and know-how of ABLIC Inc. The information described herein does not convey any license under any intellectual property rights or any other rights belonging to ABLIC Inc. or a third party. Reproduction or copying of the information from this document or any part of this document described herein for the purpose of disclosing it to a third-party without the express permission of ABLIC Inc. is strictly prohibited.
- 14. For more details on the information described herein, contact our sales office.

2.0-2018.01

